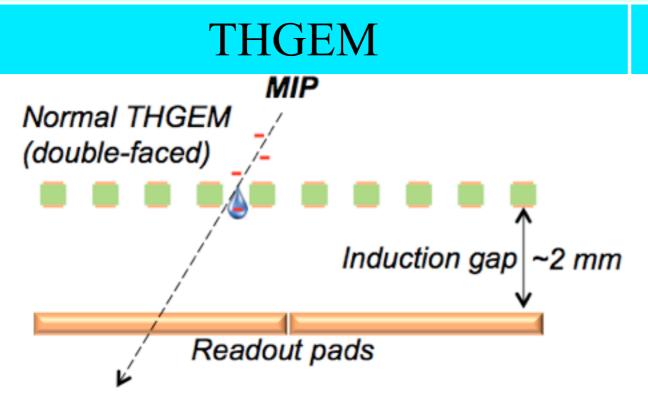
# **Resistive WELL** THGEM-based resistive concepts

S. Bressler on behalf of the WIS/Coimbra/Aveiro groups

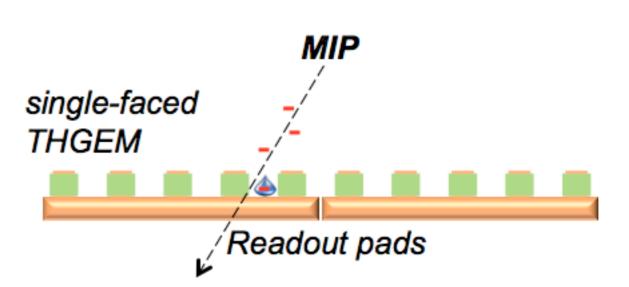
# Points for consideration

- Performance of resistive detector is characterized in terms of
  - Efficiency & spatial resolution
    - Pad multiplicity in 'our' case
  - Discharge probability
  - Discharge energy
  - Rate capabilities
    - Gain at different rates (linear current response)
    - Gain at different primary ionization
  - Aging
    - Also of resistive material
    - Not yet studied by us

# THGEM Vs. WELL



- Discharge often between the top and bottom THGEM electrodes
  - Energy reaches also the anode fraction depends on the size and field in the induction gap
- In presence of resistive THGEM/anode separation charge accumulating on the anode is assumed to have small effect on the field inside the THGEM hole ⇒ resistive concepts more suitable to the WELL configuration



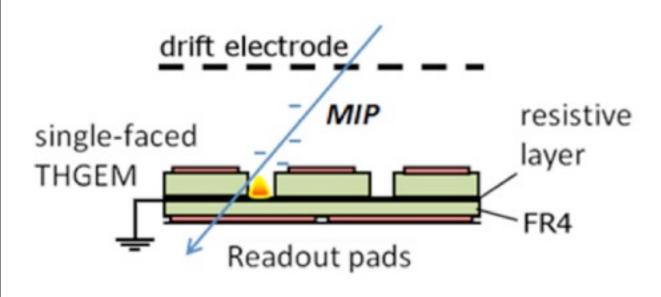
WELL

- Discharge between the top electrode and anode
- All the energy reaches the anode
- In presence of resistive WELL/anode separation - charge accumulating on the anode reduces the field in the bottom of the hole ⇒ quenching the discharge energy

# RWELL & SRWELL

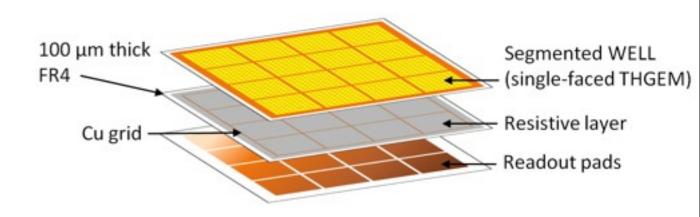
#### **Resistive WELL**

- Exploits technologies developed at WIS for the Thin Gap Chambers
- Well coupled to a resistive layer (1-20MΩ/square) - graphite epoxy mixture
- Pads separated from the RL by thin insulating sheet
- Charge induced in the readout pads
- RL quenches discharge energy
  - Not reducing their rate (?)



#### Segmented Resistive WELL

- Cross talk due to charge propagation across the RL is avoided by adding a Cu greed underneath
- The electrode is segmented accordingly to prevent discharge in holes residing directly above grid lines



- Reintroducing direct path between conductive areas on the electrode and the anode
- Conceptually, degrades uniformity

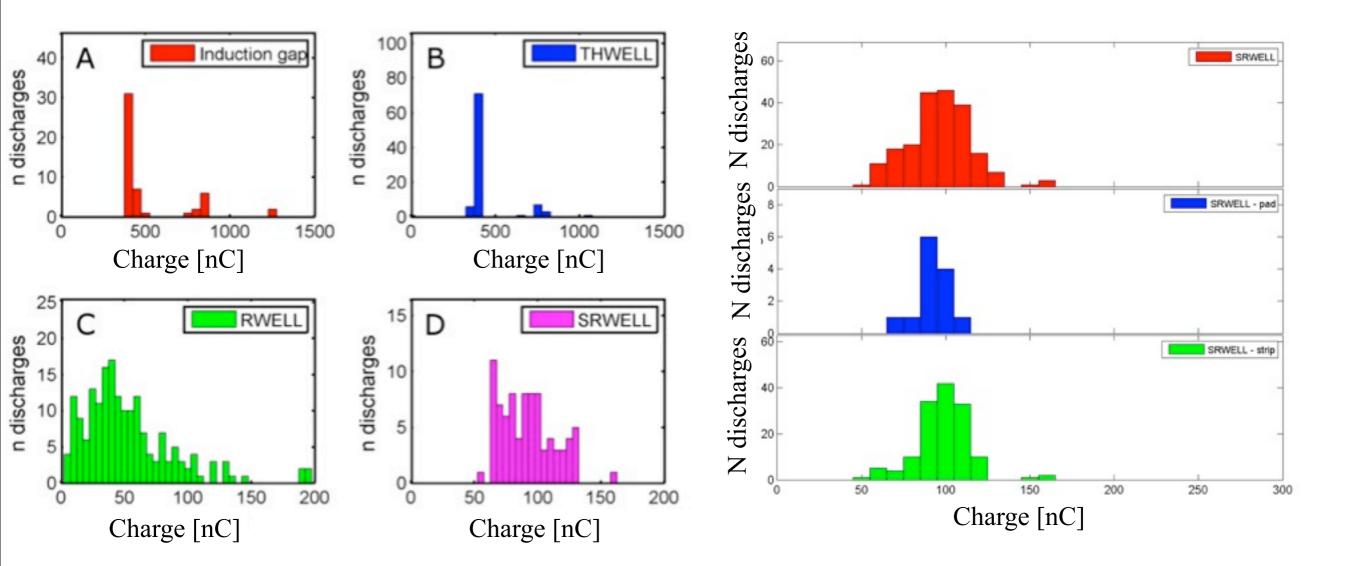
4

# RWELL & SRWELL

L. Arazi et. al. JINST 9 (2014) P04011 L. Arazi et. al. JINST 7 (2012) C05011

- Spark energy magnitude quenched by a factor of 20/5 in SRWELL/RWELL
- Cu strip reduces the quenching

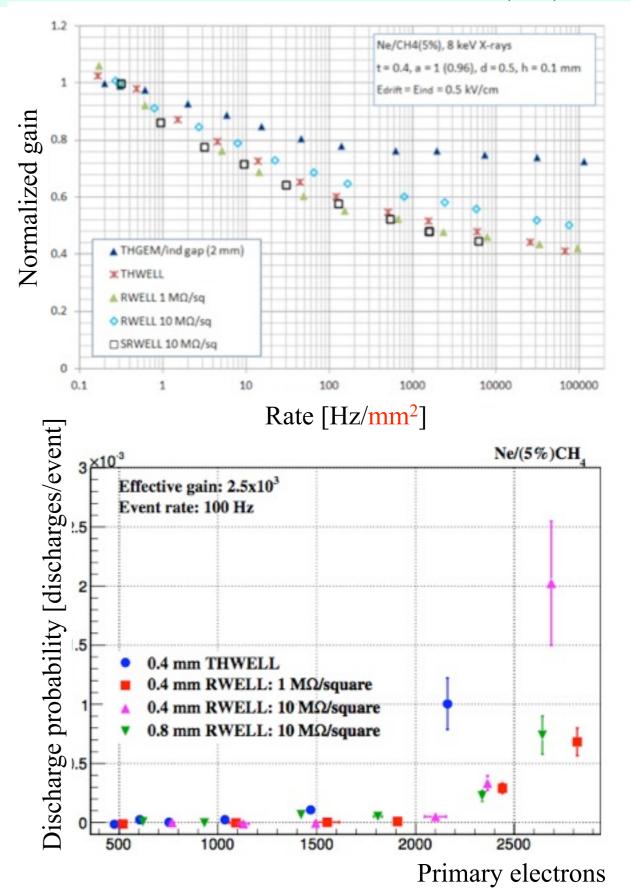
• Spark magnitude not affected by the distance from the strips



# RWELL & SRWELL

L. Arazi et. al. JINST 9 (2014) P04011
L. Arazi et. al. JINST 7 (2012) C05011
S. Bressler et. al. JINST 9 (2014) P030051

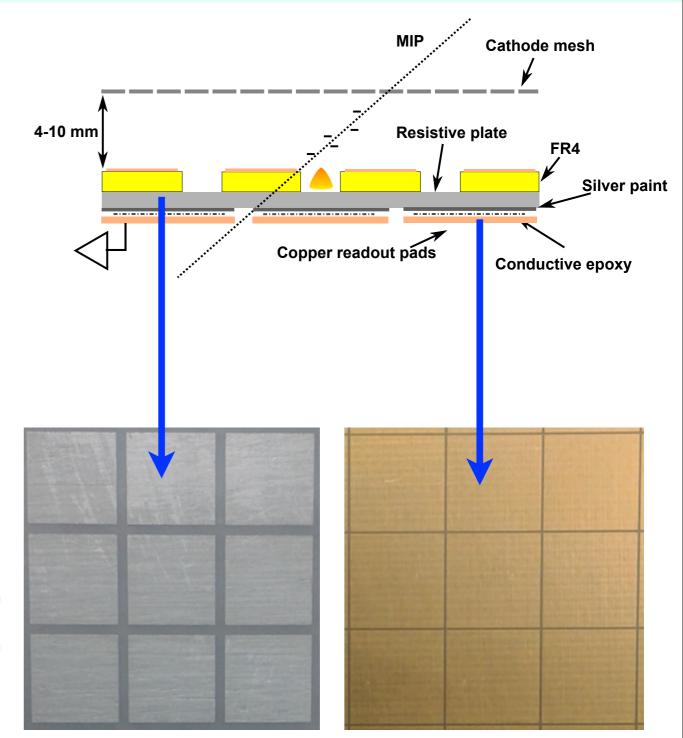
- Gain loss at high rate
  - Similar regardless of the resistivity value ⇒ at least part of the effect is not related to the resistive layer
- Narrow dynamic range ⇒ with this resistivity values discharges are not avoided
  - Their energy is quenched



#### Resistive Plate WELL:

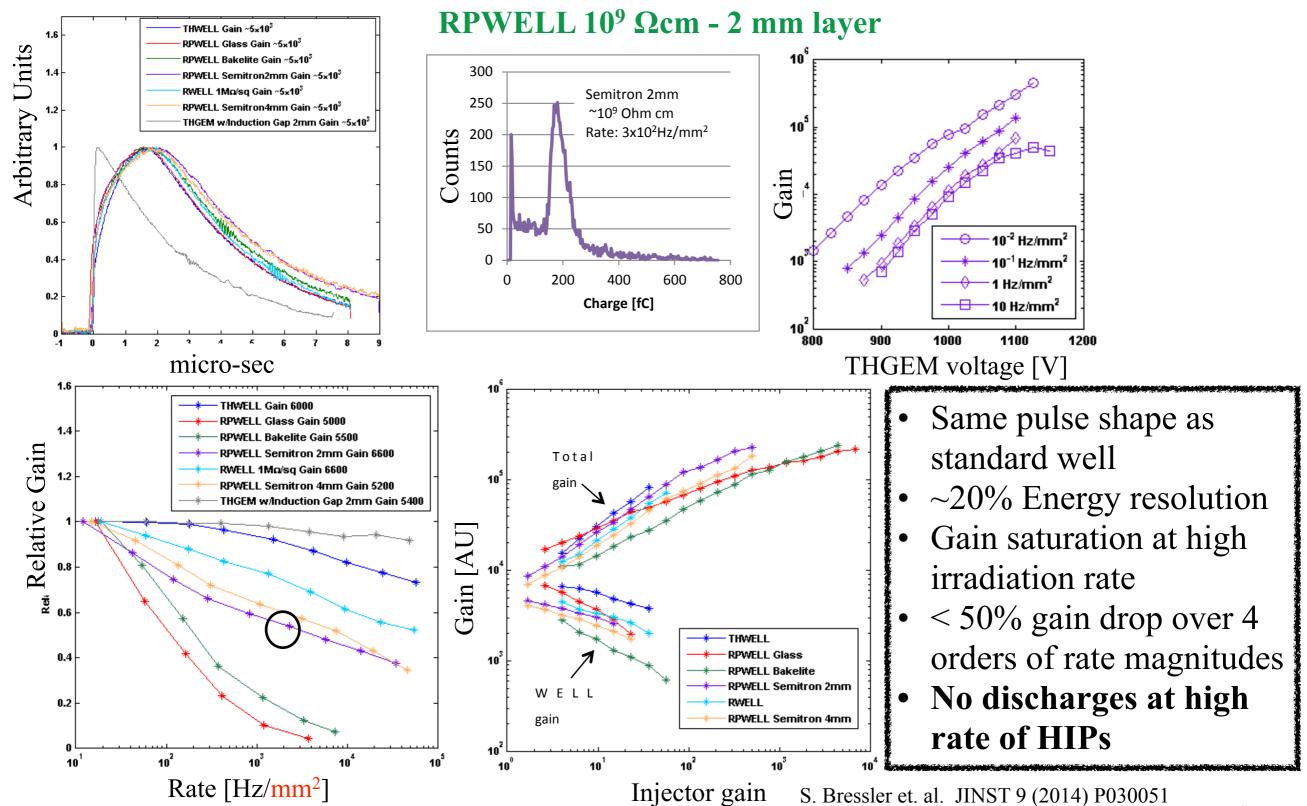
- WELL coupled to materials with large bulk resistivity
- The charge is induced on the readout pads
- The avalanche charge flows through the plate to the anode
- Uniform detector
  - Up to RP uniformity

ensions Bulk resistivity nm] [Ωcm]
81×0.4 8×10 <sup>12</sup>
29×2 2×10 <sup>10</sup>
30×2 2×10 <sup>9</sup>



#### Lab. studies

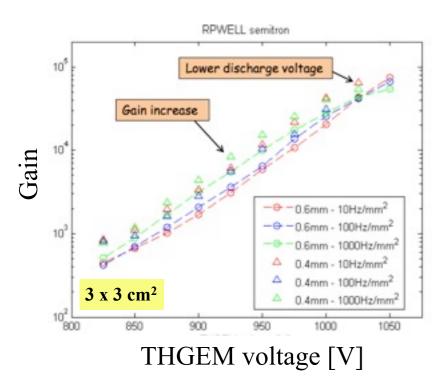
#### Characterization in Ne/5%CH4



#### Lab. studies

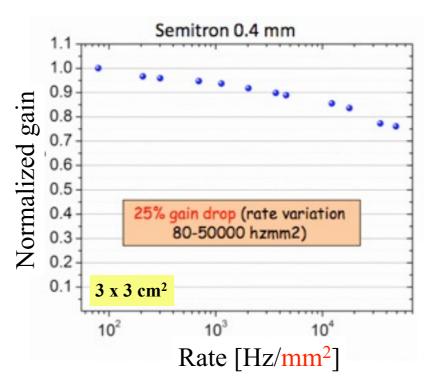
#### Characterization in Ne/5%CH4

#### Improved performance with thinner (0.4 & 0.6 mm) layers



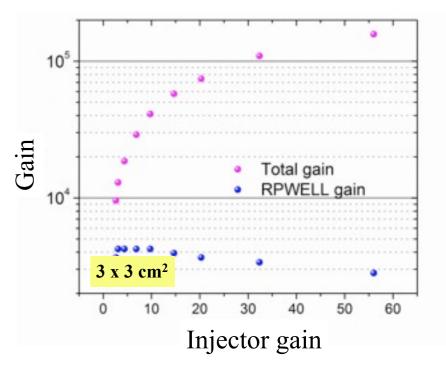
Higher gain for the same voltage

• Smaller anode-cathode gap



Gain drops slower with rate

• Lower resistivity



Stable with HIPs

• Observe gain saturation

#### Focus on thin Semitron ESD 225 layers

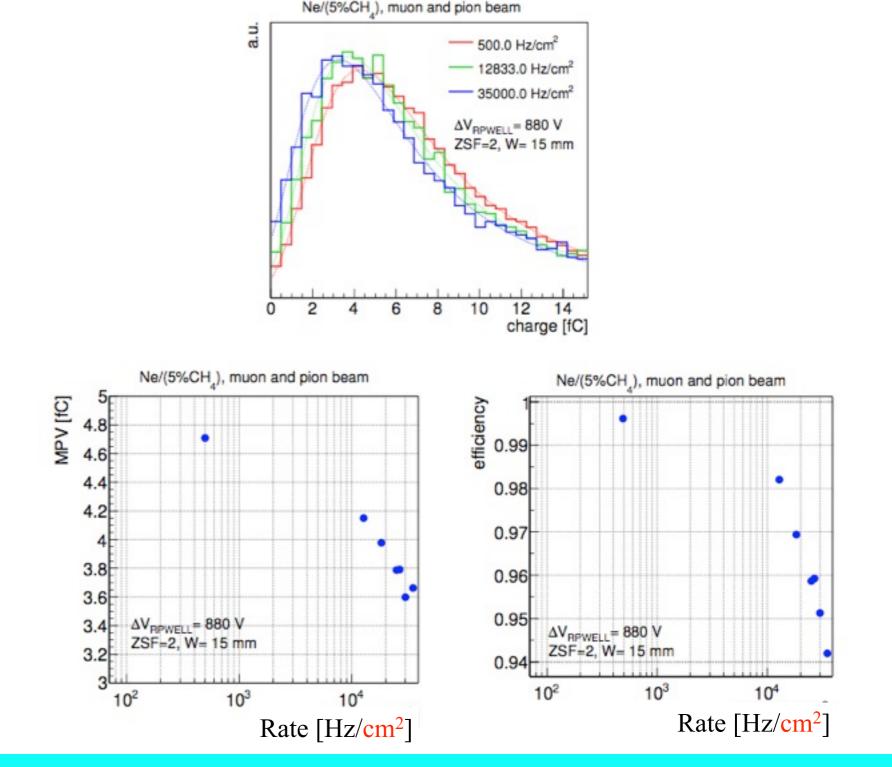
### Beam studies

### 10×10 cm<sup>2</sup> detector in Ne/5%CH<sub>4</sub>

### 150 GeV $\mu$ & $\pi$ beams

• ~20% gain drop over 2 orders of rate magnitudes

- ~5% efficiency loss
  - Can be avoided with slightly higher nominal operation voltage (still in discharge-free) mode



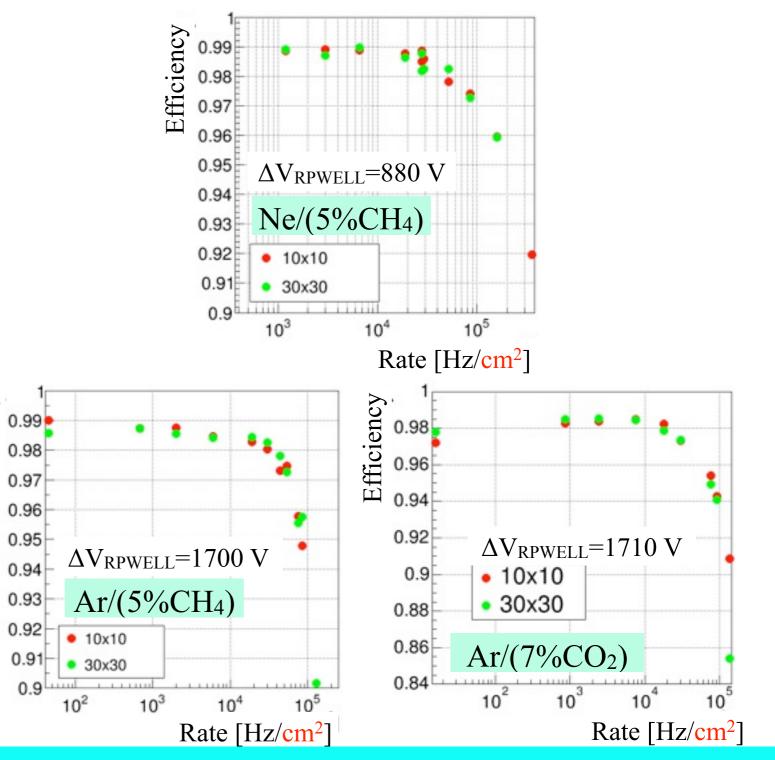
#### Discharge-free operation also at high rate $\pi$ -beam

### Beam studies

### Ne/5%CH<sub>4</sub> - Ar/5%CH<sub>4</sub> - Ar/7%CO<sub>2</sub>

### 150 GeV $\mu$ & $\pi$ beams

- Similar rate dependence for both 10×10 cm<sup>2</sup> & 30×30 cm<sup>2</sup> detectors
- ~5% efficiency loss over 3 orders of rate magnitudes
  - Can be avoided by defining higher nominal operation voltage
  - Still maintain discharge-free operation



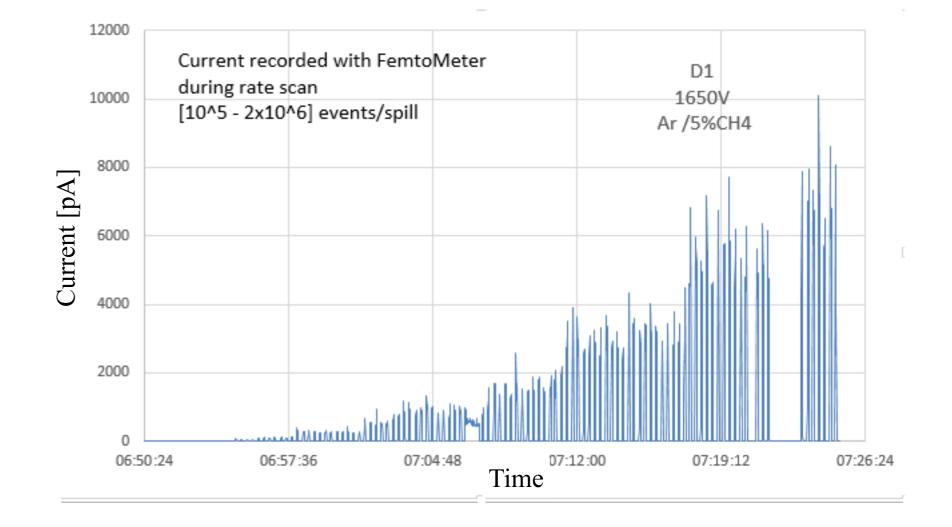
 $10 \times 10$  cm<sup>2</sup> - Discharge-free operation also at high rate  $\pi$ -beam

Efficiency

#### Beam studies

#### Ne/5%CH<sub>4</sub> - Ar/5%CH<sub>4</sub> - Ar/7%CO<sub>2</sub>

- The current increases with the rate
- 'Ohmic' behavior is observed



#### $10 \times 10$ cm<sup>2</sup> - Discharge-free operation also at high rate $\pi$ -beam

# Points for consideration

- Performance of resistive detector is characterized in terms of
  - Efficiency & spatial resolution
    - Pad multiplicity in 'our' case
  - Discharge probability
  - Discharge energy
  - <u>Rate capabilities</u>
    - Gain at different rates (linear current response)
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### Rate capabilities

- A priorly affected by
  - The resistive concept
  - The R & C (or RC) values
  - Charging up of the THGEM itself
    - Rims, wall of the holes
  - Hard to decouple the different effects

### Available 'tools'

- Measurement under different irradiation rates ⇒ fixed number of primary electrons at variable rates
- The injector method ⇒ fixed rate at variable number of primary electrons
- Different structures ⇒ mitigating the effect of charging up
- 13 For example Small rims